



Am27LV020/Am27LV020B

2 Megabit (262,144 x 8-Bit) Low Voltage CMOS EPROM

DISTINCTIVE CHARACTERISTICS

- **Single 3.3 V power supply**
 - Regulated power supply 3.0 V–3.6 V
 - Unregulated power supply 2.7 V–3.6 V (battery-operated systems)
- **Low power consumption:**
 - 10 μ A typical CMOS standby current
 - 30 μ W maximum standby power
 - 20 mW typical power at 5 MHz
- **Fast access time**
 - 150 ns
- **JEDEC-approved pinout**
 - Pin compatible with 5.0 V 2 Mbit EPROM
 - Easy upgrade from 28-pin JEDEC EPROMs
- **100% Flashrite™ programming**
 - Typical programming time of 32 seconds
- **Latch-up protected to 100 mA from –1 V to V_{CC} +1 V**
- **High noise immunity**
- **Compact 32-pin DIP package requires no hardware change for upgrades to 8 Mbit**
- **Versatile features for simple interfacing**
 - Both CMOS and TTL input/output compatibility
 - Two line control functions

GENERAL DESCRIPTION

The Am27LV020 is a low voltage, low power 2 Mbit, ultraviolet erasable, programmable read-only memory organized as 256K words by 8 bits per word.

The Am27LV020 operates from a single power supply of 3.3 V and is offered with two power supply tolerances. The Am27LV020 has a V_{CC} tolerance range of 3.3 V \pm 0.3 V making it suitable for use in systems that have regulated power supplies. The Am27LV020B has a voltage supply range of 2.7 V–3.6 V making it an ideal part for battery operated systems.

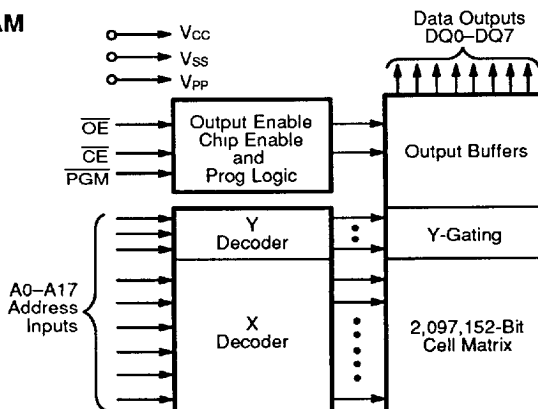
Maximum power consumption of the Am27LV020 in standby mode is only 90 μ W. If the device is constantly accessed at 5 MHz, then the maximum power consumption increases to 54 mW. These power ratings are significantly lower than typical EPROMs. Also, as power consumption is proportional to voltage squared, 3.3 V

devices consume at least 57% less power than their 5.0 V counterparts. Due to its lower current and voltage, the Am27LV020 is well-suited for battery operated and portable systems as it extends the battery life in these systems. Typical applications are notebook and hand-held computers as well as cellular phones.

The Am27LV020 is packaged in the industry standard 32-pin windowed ceramic DIP and LCC packages, as well as one-time programmable (OTP) packages. This device is pin-compatible with the 5.0 V devices.

The Am27LV020 uses AMD's Flashrite programming algorithm (100 μ s pulses) resulting in typical programming times of 32 seconds. This device is manufactured on AMD's sub-micron process technology which provides high speed, low power and high noise immunity.

BLOCK DIAGRAM

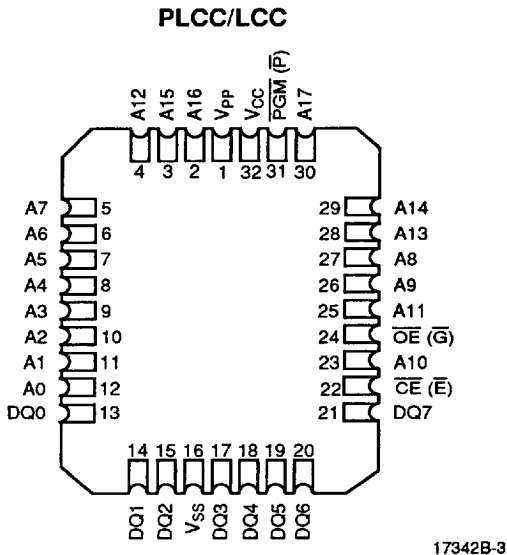
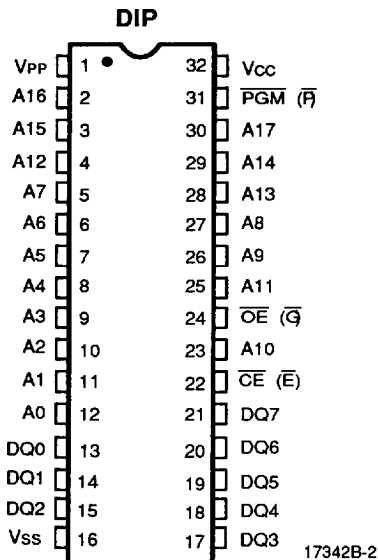


PRODUCT SELECTOR GUIDE

Family Part No	Am27LV020/Am27LV020B			
Ordering Part No:				
Am27LV020 (3.0 V–3.6 V)	-150	-200	-250	-300
Am27LV020B (2.7 V–3.6 V)		-200	-250	-300
Max Access Time (ns)	150	200	250	300
\overline{CE} (\overline{E})Access (ns)	150	200	250	300
\overline{OE} (\overline{G})Access (ns)	65	75	100	120

CONNECTION DIAGRAMS

Top View



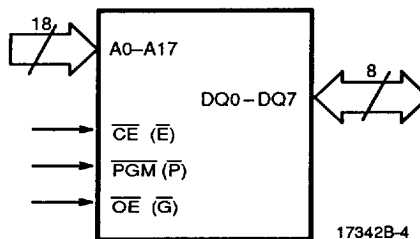
Notes:

1. JEDEC nomenclature is in parenthesis.

PIN DESCRIPTION

A0–A17 = Address Inputs
 \overline{CE} (\overline{E}) = Chip Enable Input
DQ0–DQ7 = Data Input/Outputs
 \overline{OE} (\overline{G}) = Output Enable Input
 \overline{PGM} (\overline{P}) = Program Enable Input
Vcc = Vcc Supply Voltage
VPP = Program Supply Voltage
Vss = Ground

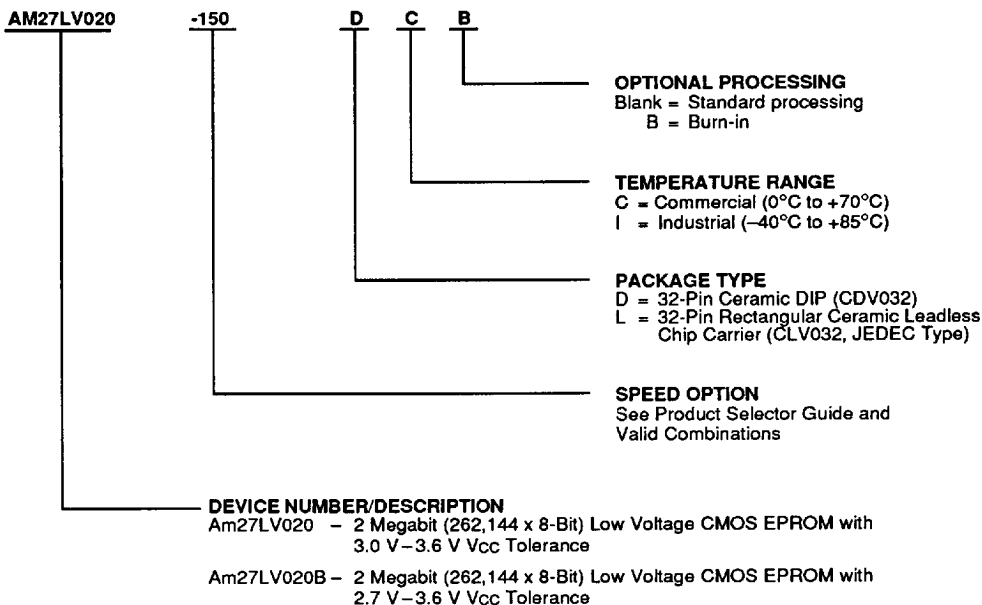
LOGIC SYMBOL



0257525 0046659 T27

ORDERING INFORMATION**EPROM Products**

AMD standard products are available in several packages and operating ranges. The order number (Valid Combination) is formed by a combination of:



Valid Combinations	
AM27LV020-150	DC, DCB, DI, DIB, LC, LCB, LI, LIB
AM27LV020-200	DC, DCB, DI, DIB, LC, LCB, LI, LIB
AM27LV020-250	
AM27LV020-300	
AM27LV020B-200	
AM27LV020B-250	
AM27LV020B-300	

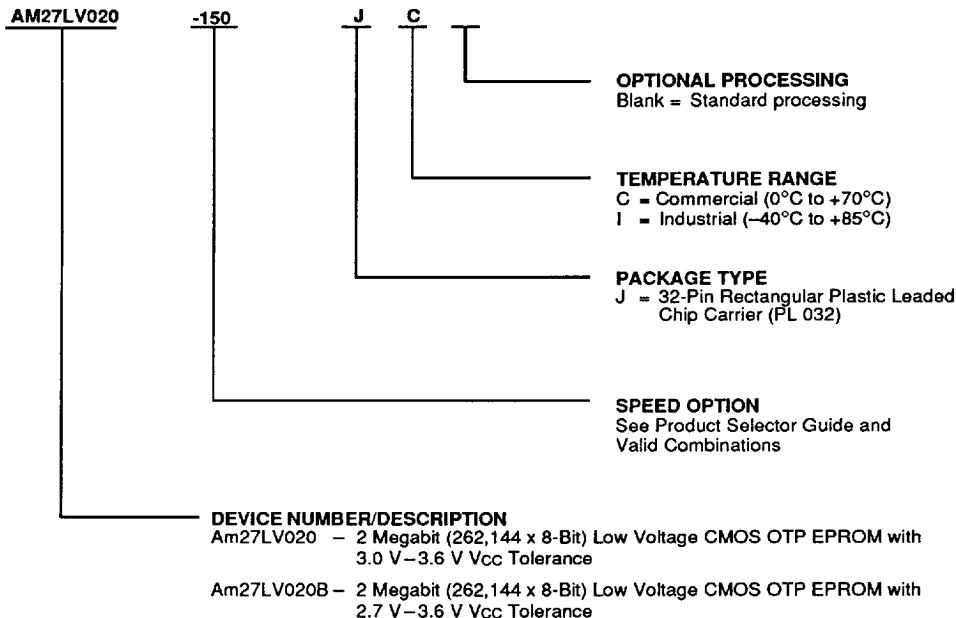
Valid Combinations

Valid Combinations list configurations planned to be supported in volume for this device. Consult the local AMD sales office to confirm availability of specific valid combinations and to check on newly released combinations.

ORDERING INFORMATION

OTP Products

AMD standard products are available in several packages and operating ranges. The order number (Valid Combination) is formed by a combination of:



Valid Combinations	
AM27LV020-150	JC, JI
AM27LV020-200	
AM27LV020-250	
AM27LV020-300	
AM27LV020B-200	
AM27LV020B-250	
AM27LV020B-300	

Valid Combinations

Valid Combinations list configurations planned to be supported in volume for this device. Consult the local AMD sales office to confirm availability of specific valid combinations and to check on newly released combinations.

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FUNCTIONAL DESCRIPTION

Erasing the Am27LV020

In order to clear all locations of their programmed contents, it is necessary to expose the Am27LV020 to an ultraviolet light source. A dosage of 15 W seconds/cm² is required to completely erase an Am27LV020. This dosage can be obtained by exposure to an ultraviolet lamp — wavelength of 2537 Å — with intensity of 12,000 μW/cm² for 15 to 20 minutes. The Am27LV020 should be directly under and about one inch from the source and all filters should be removed from the UV light source prior to erasure.

It is important to note that the Am27LV020, and similar devices, will erase with light sources having wavelengths shorter than 4000 Å. Although erasure times will be much longer than with UV sources at 2537 Å, nevertheless the exposure to fluorescent light and sunlight will eventually erase the Am27LV020 and exposure to them should be prevented to realize maximum system reliability. If used in such an environment, the package window should be covered by an opaque label or substance.

Programming the Am27LV020

Upon delivery, or after each erasure, the Am27LV020 has all 2,097,152 bits in the "ONE", or HIGH state. "ZEROS" are loaded into the Am27LV020 through the procedure of programming.

The programming mode is entered when 12.75 V ± 0.25 V is applied to the V_{PP} pin, \overline{CE} and PGM are at V_{IL} and \overline{OE} is at V_{IH}.

For programming, the data to be programmed is applied 8 bits in parallel to the data output pins.

The Flashrite algorithm reduces programming time by using 100 μs programming pulse and by giving each address only as many pulses as are necessary in order to reliably program the data. After each pulse is applied to a given address, the data in that address is verified. If the data does not verify, additional pulses are given until it verifies or the maximum is reached. This process is repeated while sequencing through each address of the Am27LV020. This part of the algorithm is done at V_{CC} = 6.25 V to assure that each EPROM bit is programmed to a sufficiently high threshold voltage. After the final address is completed, the entire EPROM memory is verified at V_{CC} = V_{PP} = 5.25 V. Am27LV020 can be programmed using the same algorithm as the 5 V counterpart Am27C020.

Please refer to Section 6 for programming flow chart and characteristics.

Program Inhibit

Programming of multiple Am27LV020s in parallel with different data is also easily accomplished. Except for \overline{CE} , all like inputs of the parallel Am27LV020 may be common. A TTL low-level program pulse applied to an Am27LV020 \overline{CE} input with V_{PP} = 12.75 ± 0.25 V, PGM LOW, and \overline{OE} HIGH will program that Am27LV020.

A high-level \overline{CE} input inhibits the other Am27LV020s from being programmed.

Program Verify

A verify should be performed on the programmed bits to determine that they were correctly programmed. The verify should be performed with \overline{OE} and \overline{CE} at V_{IL}, PGM at V_{IH}, and V_{PP} between 12.5 V and 13.0 V.

Auto Select Mode

The auto select mode allows the reading out of a binary code from an EPROM that will identify its manufacturer and type. This mode is intended for use by programming equipment for the purpose of automatically matching the device to be programmed with its corresponding programming algorithm. This mode is functional in the 25°C ± 5°C ambient temperature range that is required when programming the Am27LV020.

To activate this mode, the programming equipment must force 12.0 ± 0.5 V on address line A9 of the Am27LV020. Two identifier bytes may then be sequenced from the device outputs by toggling address line A0 from V_{IL} to V_{IH}. All other address lines must be held at V_{IL} during auto select mode.

Byte 0 (A0 = V_{IL}) represents the manufacturer code, and Byte 1 (A0 = V_{IH}), the device identifier code. For the Am27LV020, these two identifier bytes are given in the Mode Select table. All identifiers for manufacturer and device codes will possess odd parity, with the MSB (DQ7) defined as the parity bit.

Read Mode

The Am27LV020 has two control functions, both of which must be logically satisfied in order to obtain data at the outputs. Chip Enable (\overline{CE}) is the power control and should be used for device selection. Output Enable (\overline{OE}) is the output control and should be used to gate data to the output pins, independent of device selection. Assuming that addresses are stable, address access time (t_{ACC}) is equal to the delay from \overline{CE} to output (t_{CE}). Data is available at the outputs t_{OE} after the falling edge of \overline{OE} , assuming that \overline{CE} has been LOW and addresses have been stable for at least t_{ACC} - t_{CE}.

Standby Mode

The Am27LV020 has a CMOS standby mode which reduces the maximum V_{CC} current to 25 μA. It is placed in CMOS-standby when \overline{CE} is at V_{CC} ± 0.3 V. The Am27LV020 also has a TTL-standby mode which reduces the maximum V_{CC} current to 0.6 mA. It is placed in TTL-standby when \overline{CE} is at V_{IH}. When in standby mode, the outputs are in a high-impedance state, independent of the \overline{OE} input.

Mixed Power Supply System

Am27LV020 (in 3.0 V to 3.6 V regulated power supply) can be interfaced with 5 V system only when the I/O pins (DQ0-DQ7) are not driven by the 5 V system. V_{IHmax} = V_{CCCLV} + 2.2 V for address and clock pins and

$V_{IHmax} = V_{CCLV} + 0.5 \text{ V}$ for I/O pins should be followed to avoid CMOS latch-up condition.

Output OR-Tieing

To accommodate multiple memory connections, a two-line control function is provided to allow for:

- Low memory power dissipation
- Assurance that output bus contention will not occur

It is recommended that \overline{CE} be decoded and used as the primary device-selecting function, while \overline{OE} be made a common connection to all devices in the array and connected to the READ line from the system control bus. This assures that all deselected memory devices are in their low-power standby mode and that the output pins are only active when data is desired from a particular memory device.

System Applications

During the switch between active and standby conditions, transient current peaks are produced on the rising and falling edges of Chip Enable. The magnitude of these transient current peaks is dependent on the output capacitance loading of the device. At a minimum, a $0.1 \mu\text{F}$ ceramic capacitor (high frequency, low inherent inductance) should be used on each device between V_{CC} and V_{SS} to minimize transient effects. In addition, to overcome the voltage drop caused by the inductive effects of the printed circuit board traces on EPROM arrays, a $4.7 \mu\text{F}$ bulk electrolytic capacitor should be used between V_{CC} and V_{SS} for each eight devices. The location of the capacitor should be close to where the power supply is connected to the array.

MODE SELECT TABLE

Mode \ Pins		\overline{CE}	\overline{OE}	\overline{PGM}	A0	A9	V _{PP}	Outputs
Read		V _{IL}	V _{IL}	X	X	X	X	DOUT
Output Disable		V _{IL}	V _{IH}	X	X	X	X	High Z
Standby (TTL)		V _{IH}	X	X	X	X	X	High Z
Standby (CMOS)		$V_{CC} \pm 0.3 \text{ V}$	X	X	X	X	X	High Z
Program		V _{IL}	V _{IH}	V _{IL}	X	X	V _{PP}	DIN
Program Verify		V _{IL}	V _{IL}	V _{IH}	X	X	V _{PP}	DOUT
Program Inhibit		V _{IH}	X	X	X	X	V _{PP}	High Z
Auto Select (Note 3)	Manufacturer Code	V _{IL}	V _{IL}	X	V _{IL}	V _H	X	01H
	Device Code	V _{IL}	V _{IL}	X	V _{IH}	V _H	X	97H

Notes:

1. $V_H = 12.0 \text{ V} \pm 0.5 \text{ V}$
2. X can be either V_{IL} or V_{IH}
3. A1–A8 = A10–A17 = V_{IL}
4. See DC Programming Characteristics for V_{PP} voltage during programming.

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ABSOLUTE MAXIMUM RATINGS

Storage Temperature:	
OTP Products	–65°C to +125°C
All Other Products	–65°C to +150°C
Ambient Temperature	
with Power Applied	–55°C to +125°C
Voltage with Respect to V _{SS} :	
All pins except A9, V _{PP} , and	
V _{CC} (Note 1)	–0.6 V to V _{CC} + 0.6 V
A9 and V _{PP} (Note 2)	–0.6 V to 13.5 V
V _{CC}	–0.6 V to 7.0 V

Notes:

1. During transitions, the input may overshoot V_{SS} to –2.0 V for periods of up to 20 ns. Maximum DC voltage on input and I/O may overshoot to V_{CC} + 2.0 V for periods of up to 20 ns.
2. During transitions, A9 and V_{PP} may overshoot V_{SS} to –2.0 V for periods of up to 20 ns. A9 and V_{PP} must not exceed 13.5 V for any period of time.

Stresses above those listed under Absolute Maximum Ratings may cause permanent device failure. Functionality at or above these limits is not implied. Exposure to absolute maximum ratings for extended periods may affect device reliability.

OPERATING RANGES**Commercial (C) Devices**

Case Temperature (T _C)	0°C to +70°C
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Industrial (I) Devices

Case Temperature (T _C)	–40°C to +85°C
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Supply Read Voltages:

V _{CC} for Am27LV020	+3.0 V to +3.6 V
V _{CC} for Am27LV020B	+2.7 V to +3.6 V

Operating ranges define those limits between which the functionality of the device is guaranteed.

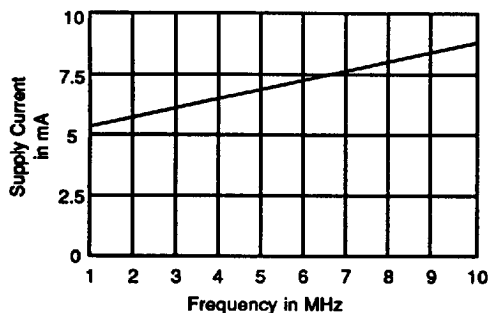
DC CHARACTERISTICS over operating ranges unless otherwise specified (Notes 1, 2, 3, and 4)

Parameter Symbol	Parameter Description	Test Conditions	Min	Max	Unit
TTL and CMOS Inputs for Am27LV020 ($V_{CC} = 3.0 \text{ V to } 3.6 \text{ V}$)					
V_{OH}	Output HIGH Voltage	$I_{OH} = -2.0 \text{ mA}$	2.4		V
V_{OL}	Output LOW Voltage	$I_{OL} = 2.0 \text{ mA}$		0.4	V
V_{IH}	Input HIGH Voltage		2.0	$V_{CC} + 0.3$	V
V_{IL}	Input LOW Voltage		-0.3	+0.8	V
I_{LI}	Input Load Current	$V_{IN} = 0 \text{ V to } V_{CC}$		1.0	μA
I_{LO}	Output Leakage Current	$V_{OUT} = 0 \text{ V to } V_{CC}$		5.0	μA
I_{CC1}	V_{CC} Active Current (Note 3)	$\overline{OE} = V_{IL}$, $f = 5 \text{ MHz}$, $I_{OUT} = 0 \text{ mA}$ (Open Outputs)		15	mA
I_{CC2}	V_{CC} TTL Standby Current	$\overline{OE} = V_{IH}$, $\overline{OE} = V_{IL}$ TTL		0.6	mA
I_{CC3}	V_{CC} CMOS Standby Current	$\overline{OE} = V_{CC} \pm 0.3 \text{ V}$ CMOS		25	μA
I_{PP1}	V_{PP} Current During Read	$\overline{OE} = \overline{OE} = V_{IL}$, $V_{PP} = V_{CC}$		1.0	μA

Parameter Symbol	Parameter Description	Test Conditions	Min	Max	Unit
CMOS for Am27LV020B ($V_{CC} = 2.7 \text{ V to } 3.6 \text{ V}$)					
V_{OH}	Output HIGH Voltage	$I_{OH} = -20 \mu\text{A}$	$V_{CC} - 0.1$		V
		$I_{OH} = -100 \mu\text{A}$	$V_{CC} - 0.2$		V
V_{OL}	Output LOW Voltage	$I_{OL} = 20 \mu\text{A}$		0.1	V
		$I_{OL} = 100 \mu\text{A}$		0.2	V
V_{IH}	Input HIGH Voltage		2.0	$V_{CC} + 0.3$	V
V_{IL}	Input LOW Voltage		-0.3	0.8	V
I_{LI}	Input Load Current	$V_{IN} = 0 \text{ V to } +V_{CC}$		1.0	μA
I_{LO}	Output Leakage Current	$V_{OUT} = 0 \text{ V to } +V_{CC}$		5.0	μA
I_{CC1}	V_{CC} Active Current (Note 3)	$\overline{OE} = V_{IL}$, $f = 5 \text{ MHz}$, $I_{OUT} = 0 \text{ mA}$ (Open Outputs)		15	mA
I_{CC2}	V_{CC} TTL Standby Current	$\overline{OE} = V_{IH}$, $\overline{OE} = V_{IL}$ TTL		0.6	mA
I_{CC3}	V_{CC} CMOS Standby Current	$\overline{OE} = V_{CC} \pm 0.3 \text{ V}$		25	μA
I_{PP1}	V_{PP} Supply Current (Read)	$\overline{OE} = \overline{OE} = V_{IL}$, $V_{PP} = V_{CC}$		1.0	μA

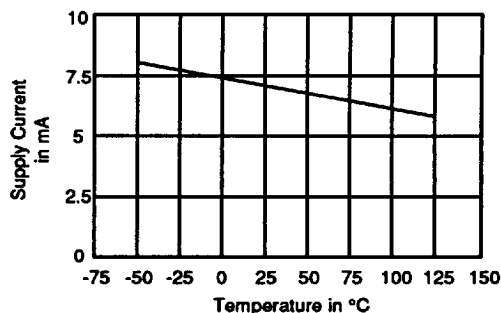
Notes:

- V_{CC} must be applied simultaneously or before V_{PP} , and removed simultaneously or after V_{PP} .
- Caution:** The Am27LV020 must not be removed from (or inserted into) a socket when V_{CC} or V_{PP} is applied.
- I_{CC1} is tested with $\overline{OE} = V_{IH}$ to simulate open outputs.
- Minimum DC Input Voltage is -0.3 V. During transitions, the inputs may overshoot to -2.0 V for periods less than 20 ns. Maximum DC Voltage on output pins is $V_{CC} + 0.3 \text{ V}$, which may overshoot to $V_{CC} + 2.0 \text{ V}$ for periods less than 20 ns.



**Figure 1. Typical Supply Current
vs. Frequency**
 $V_{CC} = 3.6\text{ V}$, $T = 25^{\circ}\text{C}$

17342B-5



**Figure 2. Typical Supply Current
vs. Temperature**
 $V_{CC} = 3.6\text{ V}$, $f = 5\text{ MHz}$

17342B-6

CAPACITANCE

Parameter Symbol	Parameter Description	Test Conditions	CDV032		CLV032		PL032		Unit
			Typ	Max	Typ	Max	Typ	Max	
C _{IN}	Input Capacitance	V _{IN} = 0 V	10	12	8	10	8	10	pF
C _{OUT}	Output Capacitance	V _{OUT} = 0 V	12	15	9	12	9	12	pF

Notes:

1. This parameter is only sampled and not 100% tested.
2. $T_A = +25^{\circ}\text{C}$, $f = 1\text{ MHz}$.

SWITCHING CHARACTERISTICS over operating ranges unless otherwise specified
(Notes 1, 3, and 4)

Notes 1, 2, and 3

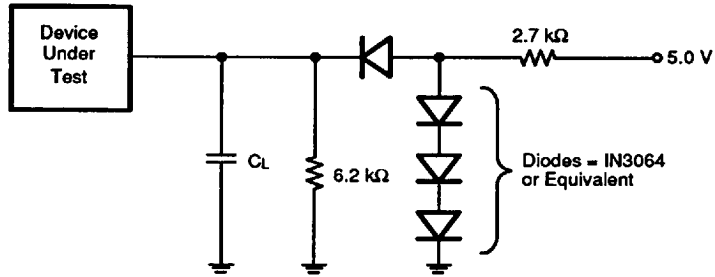
PRELIMINARY									
Parameter Symbols		Parameter Description	Test Conditions	Am27LV020/Am27LV020B					Unit
JEDEC	Standard			-150	-200	-250	-300		
tAVQV	tACC	Address to Output Delay	$\overline{CE} = \overline{OE} = V_{IL}$	Min					ns
				Max	150	200	250	300	
tELQV	tCE	Chip Enable Output Delay	$\overline{OE} = V_{IL}$	Min					ns
				Max	150	200	250	300	
tGLQV	tOE	Output Enable to Output Delay	$\overline{CE} = V_{IL}$	Min					ns
				Max	65	75	100	120	
tEHQZ	tDF (Note 2)	Chip Enable HIGH or Output Enable HIGH, whichever comes first, to Output Float		Min	0	0	0	0	ns
tGHQZ				Max	50	60	60	60	
tAXQX	tOH	Output Hold from Addresses, \overline{CE} , or \overline{OE} , whichever occurred first		Min	0	0	0	0	ns
				Max					

Notes:

1. *V_{CC} must be applied simultaneously or before V_{PP}, and removed simultaneously or after V_{PP}.*
2. *This parameter is only sampled and not 100% tested.*
3. **Caution:** *The Am27LV020 must not be removed from, or inserted into a socket or board when V_{PP} or V_{CC} is applied.*
4. *Output Load: 1 TTL gate and C_L = 100 pF,
Input Rise and Fall Times: 20 ns,
Input Pulse Levels: 0.40 V to 2.4 V,
Timing Measurement Reference Level—Inputs: 0.8 V and 2.0 V,
Outputs: 0.8 V and 2.0 V*



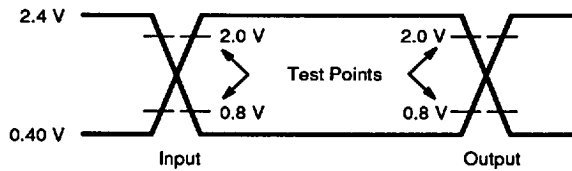
SWITCHING TEST CIRCUIT



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 $C_L = 100$ pF including jig capacitance






SWITCHING TEST WAVEFORM



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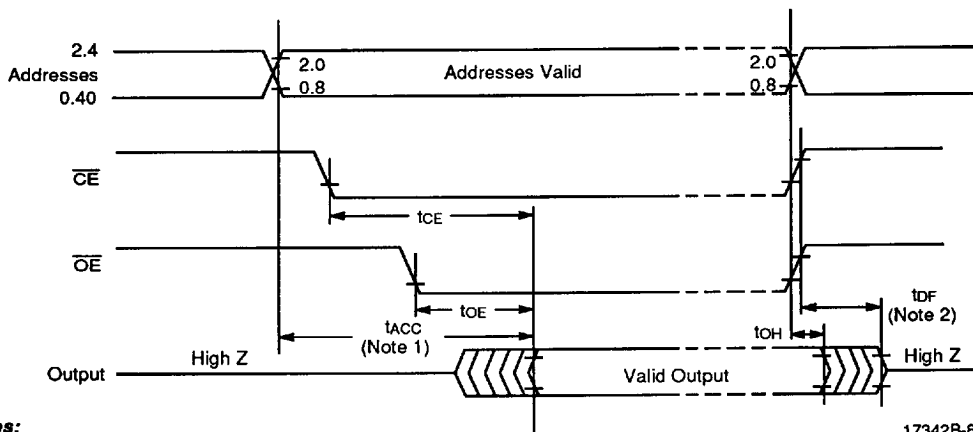
AC Testing: Inputs are driven at 2.4 V for a Logic "1" and 0.40 V for a Logic "0". Input pulse rise and fall times are ≤ 20 ns.

KEY TO SWITCHING WAVEFORMS

WAVEFORM	INPUTS	OUTPUTS
	Must Be Steady	Will Be Steady
	May Change from H to L	Will Be Changing from H to L
	May Change from L to H	Will Be Changing from L to H
	Don't Care, Any Change Permitted	Changing, State Unknown
	Does Not Apply	Center Line is High Impedance "Off" State

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SWITCHING WAVEFORM

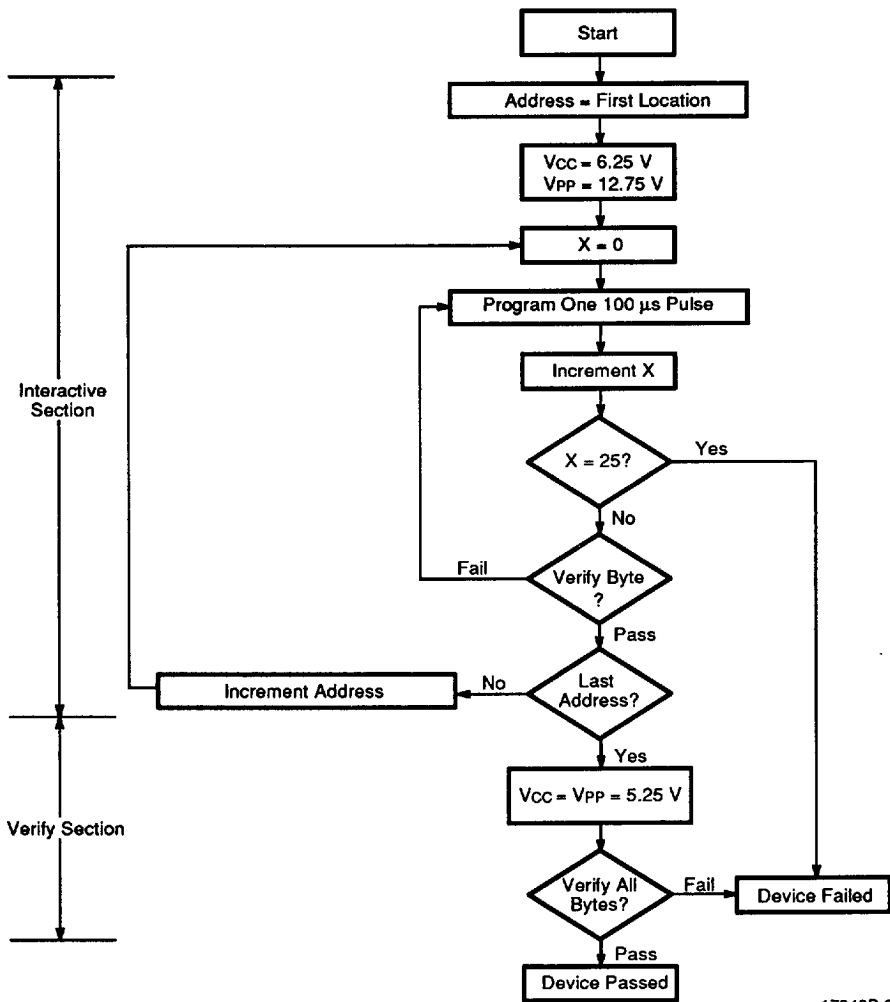


Notes:

- \overline{OE} may be delayed up to $t_{ACC} - t_{OE}$ after the falling edge of the addresses without impact on t_{ACC} .
- t_{DF} is specified from \overline{OE} or \overline{CE} , whichever occurs first.

17342B-8

PROGRAMMING FLOW CHART



17342B-9

Figure 1. Flashrite Programming Flow Chart

DC PROGRAMMING CHARACTERISTICS ($T_A = +25^{\circ}\text{C} \pm 5^{\circ}\text{C}$) (Notes 1, 2, and 3)

Parameter Symbol	Parameter Description	Test Conditions	Min	Max	Unit
I_{LI}	Input Current (All Inputs)	$V_{IN} = V_{IL} \text{ or } V_{IH}$		10.0	μA
V_{IL}	Input LOW Level (All Inputs)		-0.3	0.8	V
V_{IH}	Input HIGH Level		3.0	$V_{CC} + 0.5$	V
V_{OL}	Output LOW Voltage During Verify	$I_{OL} = 2.1 \text{ mA}$		0.45	V
V_{OH}	Output HIGH Voltage During Verify	$I_{OH} = -400 \mu\text{A}$	2.4		V
V_H	A ₉ Auto Select Voltage		11.5	12.5	V
I_{CC}	V _{CC} Supply Current (Program & Verify)			50	mA
I_{PP}	V _{PP} Supply Current (Program)	$\overline{CE} = V_{IL}, \overline{OE} = V_{IH}$		30	mA
V_{CC}	Flashrite Supply Voltage		6.00	6.50	V
V_{PP}	Flashrite Programming Voltage		12.5	13.0	V

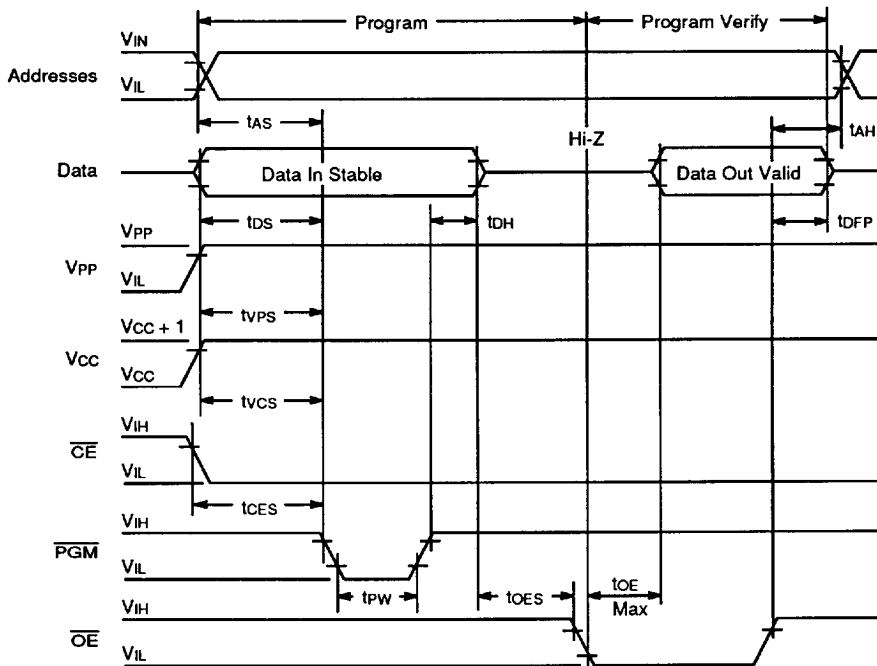
SWITCHING PROGRAMMING CHARACTERISTICS ($T_A = +25^{\circ}\text{C} \pm 5^{\circ}\text{C}$) (Notes 1, 2, and 3)

Parameter Symbols		Parameter Description	Min	Max	Unit
JEDEC	Standard				
t_{AVEL}	t_{AS}	Address Setup Time	2		μs
t_{OZGL}	t_{OES}	\overline{OE} Setup Time	2		μs
t_{DVEL}	t_{DS}	Data Setup Time	2		μs
t_{GHAX}	t_{AH}	Address Hold Time	0		μs
t_{EHDX}	t_{DH}	Data Hold Time	2		μs
t_{GHQZ}	t_{DFP}	Output Enable to Output Float Delay	0	130	ns
t_{VPS}	t_{VPS}	V _{PP} Setup Time	2		μs
t_{ELEH1}	t_{PW}	PGM Initial Program Pulse Width	95	105	μs
t_{VCS}	t_{VCS}	V _{CC} Setup Time	2		μs
t_{ELPL}	t_{CES}	\overline{CE} Setup Time	2		μs
t_{GLQV}	t_{OE}	Data Valid from \overline{OE}		150	ns

Notes:

1. V_{CC} must be applied simultaneously or before V_{PP}, and removed simultaneously or after V_{PP}.
2. When programming the Am27LV020, a 0.1 μF capacitor is required across V_{PP} and ground to suppress spurious voltage transients which may damage the device.
3. Programming characteristics are sampled but not 100% tested at worst-case conditions.

INTERACTIVE AND FLASHRITE PROGRAMMING ALGORITHM WAVEFORM (Notes 1 and 2)



Notes:

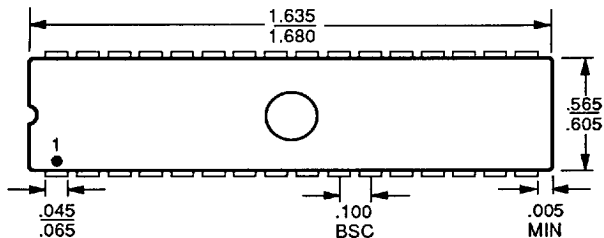
17342B-10

1. The input timing reference level is 0.8 V for V_{IL} and 3 V for V_{IH} .
2. t_{OE} and t_{DFP} are characteristics of the device, but must be accommodated by the programmer.

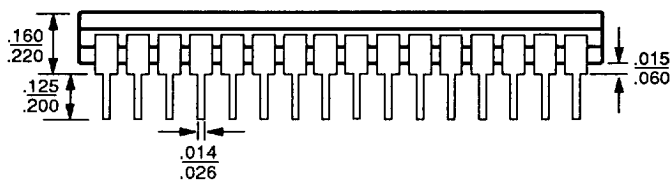
PHYSICAL DIMENSIONS*

CDV032

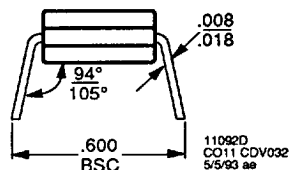
32-Pin Ceramic DIP (measured in inches)



TOP VIEW

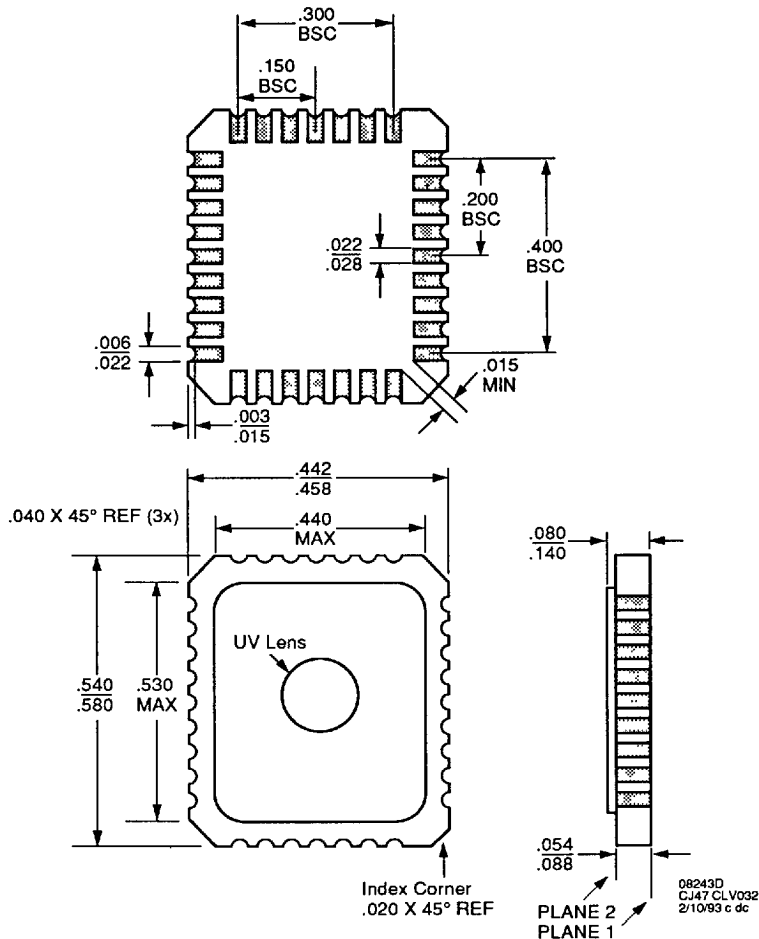


SIDE VIEW



END VIEW

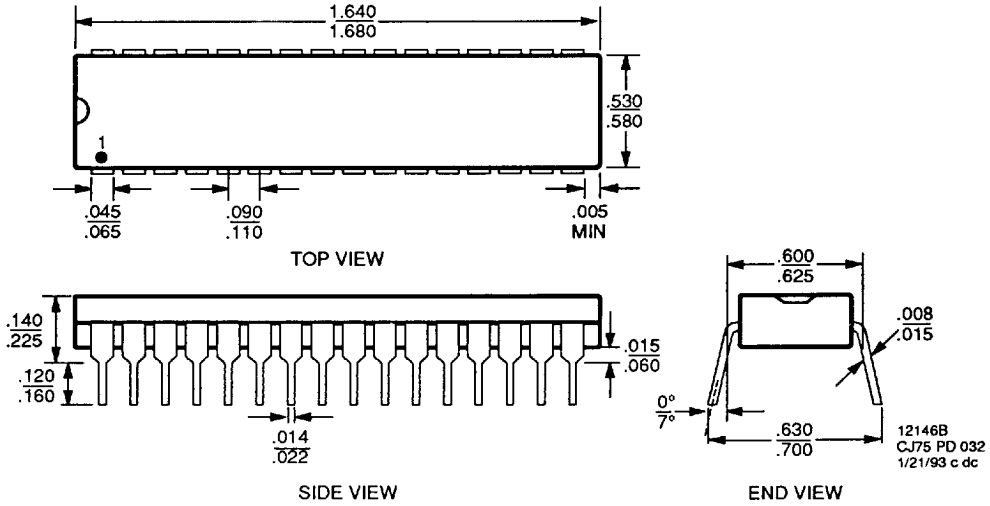
11092D
CO11 CDV032
5/5/93 ae

PHYSICAL DIMENSIONS***CLV032****32-Pin Rectangular Ceramic Leadless Chip Carrier (measured in inches)**

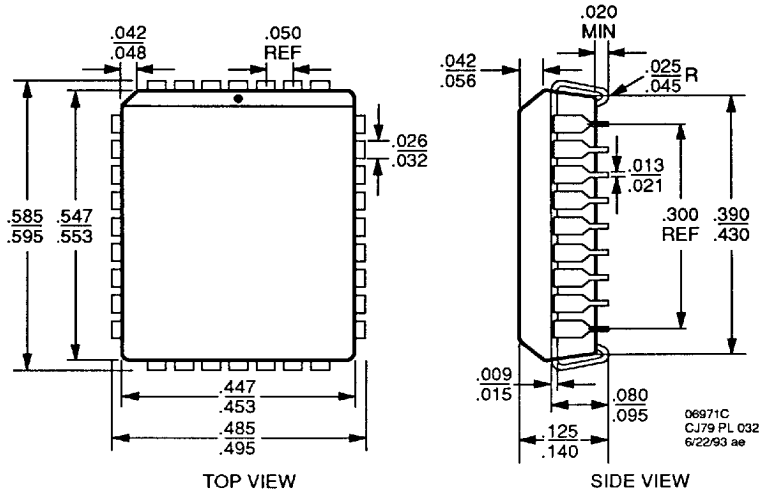
PHYSICAL DIMENSIONS*

PD 032

32-Pin Plastic DIP (measured in inches)



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PHYSICAL DIMENSIONS***PL 032****32-Pin Rectangular Plastic Leaded Chip Carrier (measured in inches)**

*For reference only. BSC is an ANSI standard for Basic Space Centering.